Date Created: 3/3/2004
Date Issued: 3/10/2004
PCN # 20040605-A

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is the first revision of the PCN 20040605 to issue Final PCN.
This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

If you have any questions concerning this change, please contact:

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PCN Originator

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REL Engineer

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PCN Type: Alternate Assembly/Test Location/Qualification

Effectivity
Expected 1st Device Shipment Date: 5/17/2004
Earliest Year/Work Week of Changed Product: 0421
(Note: Package marking may differ from this format)

Product ID (Description):
All BJT and MOSFET devices packaged in TO-3P.

Description of Change:
Wooseok S. Tech Corporation in Korea will be qualified as an alternative assembly and test site for Fairchild's BJT and MOSFET devices in the TO-3P package.
These products will be continuously assembled and tested by the existing qualified suppliers such as ENOCH and SP in Korea.

Effect of Change:
This change will not affect any electrical characteristics & reliability.
The change will enlarge the production capacity to meet customer's needs.
There is no difference in assembly materials or packing materials.
Under Fairchild's control, the same testing program will be applied to test the products from the Wooseok Location.

Qualification:
The qualification plan is intended to meet our criteria for qualifying an alternative assembly & test site, the overall quality and reliability of our products.

Qual/REL Plan Numbers

Additional Qualification Data
* The FQA9N90C is a representative device for this reliability test results.

Item	Test condition	Sample Size	Result	Test Hour
HTRB	Ta=125'C , Vds=720V, Vgs=0V	77 ea * 1lot	0/77	1000hr
HTGB	Ta=150'C , Vds=0V, Vgs=30V	77ea * 1lot	0/77	1000hr
ACLV	Ta=121'C, RH=100%, 15 PSIG	77 ea * 1lot	0/77	96 hr
TMCL	Air to air, - 65'C ~ 150'C	77 ea * 1lot	0/77	500 Cycle

* The KSE13009L is a representative device for this reliability test results.

Item	Test condition	Sample Size	Result	Test Hour
HTRB	Ta=125'C , Vds=720V, Vgs=0V	77 ea * 1lot	0/77	1000hr
ACLV	Ta=121'C, RH=100%, 15 PSIG	77 ea * 1lot	0/77	96 hr
TMCL	Air to air, - 65'C ~ 150'C	77 ea * 1lot	0/77	500 Cycle

Affected FSIDs

FJA13009TU
FJA3835TU
FJA4210OTU
FJA4210RTU
FJA4210YTU
FJA4213OTU
FJA4213RTU
FJA4310OTU
FJA4310RTU
FJA4310YTU
FJA4313OTU
FJA4313RTU
FQA10N60C
FQA10N80
FQA10N80C
FQA11N40
FQA11N90
FQA11N90C
FQA12N60
FQA12P20
FQA13N50
FQA13N80
FQA140N10
FQA14N30
FQA15N70
FQA160N08
FQA16N25
FQA16N50
FQA170N06
FQA17N40
FQA17P10
FQA18N50V2
FQA19N20
FQA19N20L
FQA19N60
FQA20N40
FQA22N30
FQA22P10
FQA24N50
FQA24N50F
FQA24N60
FQA27N25
FQA28N15
FQA28N50
FQA28N50F
FQA30N40
FQA33N10
FQA33N10L

FQA34N20
FQA34N20L
FQA34N25
FQA35N40
FQA36P15
FQA38N30
FQA40N25
FQA44N08
FQA44N10
FQA44N30
FQA46N15
FQA48N20
FQA55N10
FQA55N25
FQA58N08
FQA5N90
FQA65N06
FQA65N20
FQA6N70
FQA6N80
FQA6N90
FQA6N90C
FQA70N08
FQA70N10
FQA70N15
FQA7N60
FQA7N80
FQA7N80C
FQA7N90
FQA85N06
FQA8N80
FQA8N80C
FQA8N90C
FQA90N08
FQA90N15
FQA9N50
FQA9N90
FQA9N90C
FQA9P25
IRFP140A
IRFP150A
IRFP240B_FP001
IRFP244B_FP001
IRFP250B_FP001
IRFP254B_FP001
IRFP340B
IRFP350A
IRFP440B
IRFP450B
IRFP460C
KSA3010OTU
KSA3010RTU
KSC2751RTU
KSC3552NTU
KSC3552OTU
KSC3552RTU
KSC4010OTU
KSC4010RTU
KSC5024OTU
KSC5024RTU
KSC5024YTU
KSC5025OTU
KSC5025RTU
KSC5025YTU
KSC5029OTU
KSC5029RTU
KSC5030OTU
KSC5047TU
KSE13009LTU
SFH154
SFH9140
SFH9154
SFH9240
SFH9244
SFH9250L
SSH10N60B
SSH22N50A
SSH70N10A
SSH7N60B
TIP140TU
TIP141LTU
TIP141TU
TIP142TU
TIP145TU
TIP146TU
TIP147TU
TIP41CPTU